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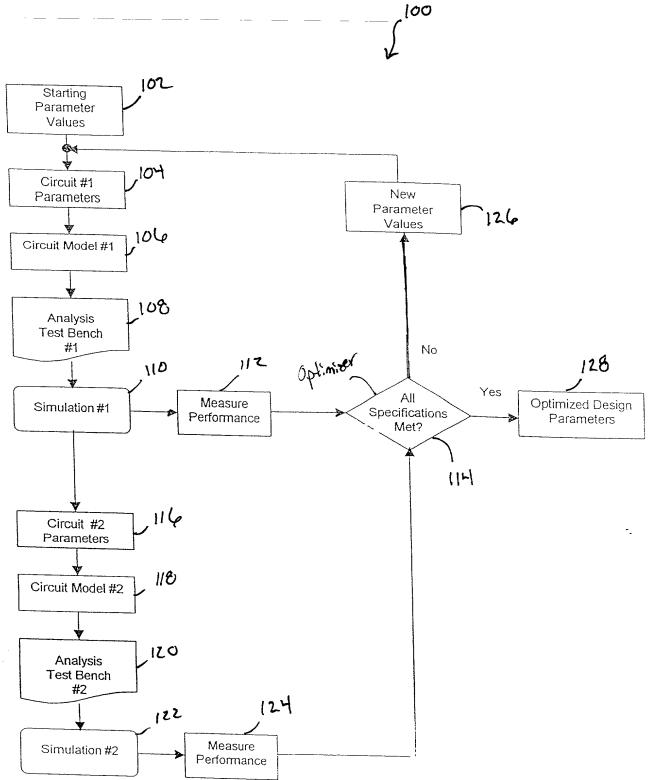
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MULTIPLE TEST BENCH OPTIMIZER Unknown

Applicant(s); Demler, et al. Attorney: Sheldon R. Meyer Phone: (415) 362-3800

Express Mail No.: EL 622 697 488 US

Sheet 1 of 4



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Sheet 2 of 4

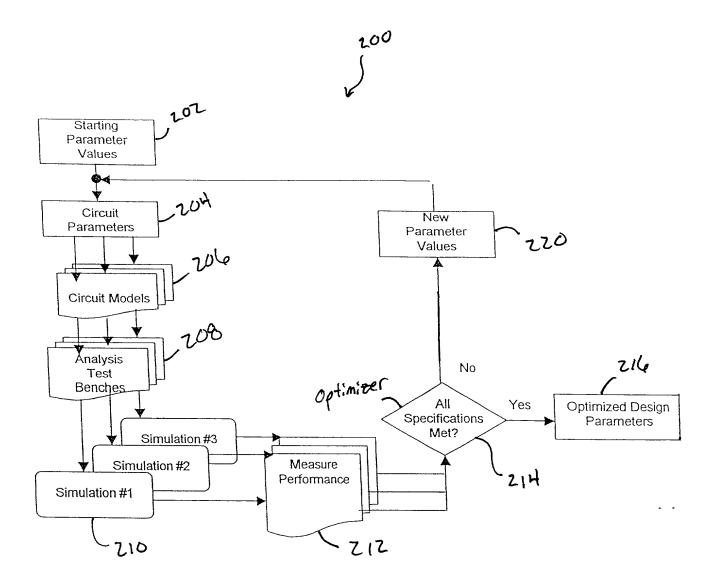
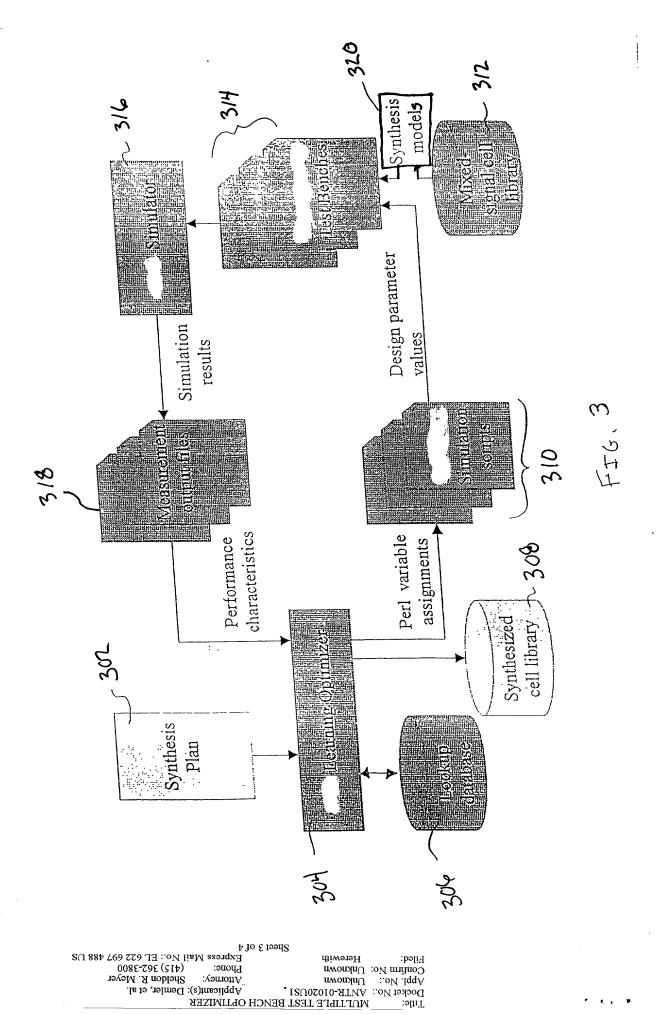


FIG. 2



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MULTIPLE TEST BENCH OPTIMIZER

Applicant(s): Demler, et al. Attorney Sheldon R. Meyer Phone: (415) 362-3800

Sheet 4 of 4

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Generate a set of circuit parameters for each performance Characteristic of a circuit

5: multaneashy pass each set of circuit parameters through a respective circuit model

Run a simulation on each circuit model on an analysis test bench in order to measure performance using the set of circuit parameters 406

Determine whether specifications were met for each simulation in an aptimizer

> Generate new parameters net? 410 Yes Optimized parameters

Figure 4